

**Search Notes**

Application/Control No.

10/670,830

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

USUI ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
updated	updated	8/2/2005	SWH
251	354	8/2/2005	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
347	86	8/2/2005	SWH
137	859	8/2/2005	SWH
251	354	8/2/2005	SWH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR